

Form PTO-1449 (Modified)

JUL 17 2002

Atty Docket No.:

003401.P002D7D1

Serial No.: 09/295,269

#22

1/5

List of Patents and Publications Statement
(Use several sheets if necessary)

Applicant: Igor Y. Khandros

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Filing Date: April 20, 1999

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

Examiner Initials		Document No.		Class	Sub- Class	Filing date if appropriate
ke	AA	4,780,836	Miyazaki et al.	364	551.01	8/6/86
ke	AB	4,634,199	Anhalt et al.	339	17 M	1/22/85
ke	AC	4,523,144	Okubo et al.	324	158 P	5/21/81
ke	AD	4,553,192	Babuka et al.	361	395	8/25/83
ke	AE	3,795,037	Luttmer	29	628	12/11/72
ke	AF	5,350,947	Takekawa et al.	257	702	10/28/92
ke	AG	4,667,219	Lee et al.	357	68	4/27/84
ke	AH	5,067,007	Kanji et al. <i>quarant</i>	357	74	1/24/91
ke	AI	5,157,325	Murphy	324	158 F	2/15/91
ke	AJ	5,218,292	Goto	324	158 F	12/9/91
ke	AK	5,399,982	Driller et al.	324	754	5/4/93

FOREIGN PATENT DOCUMENTS

No.		Document No.	Date	Country	Class	Sub- Class	Trans- lation
ke	AL	3-142847 (A)	6/18/91	Japan			No
ke	AM	54-146581	15/11/79	Japan			No
ke	AN	56-26446 (A)	3/14/81	Japan			No
ke	AO	0 500 074 A1	8/26/92	Europe			
ke	AP	0 614 089 A2	9/7/94	Europe			

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

ke	AR	Beaman et al., "ELASTOMERIC CONNECTOR FOR MCM AND TEST APPLICATIONS", ICEMM Proceedings '93, pp. 341-346.
ke	AS	"Cooling System for Semiconductor Modules", IBM Technical Disclosure Bulletin, August 1983, pp. 2 pgs. total.
ke	AT	"Method of Testing Chips and Joining Chips to Substrates", Research Disclosure, February 1991, No. 322, pp. 1.

Examiner

Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Examiner Initials		Document No.		Class	Sub- Class	Filing date if appropriate
ke	AA	5,317,479	Pai et al.	361	773	10/1/93
ke	AB	5,476,211	Khandros	228	180.5	11/16/93
ke	AC	4,085,502	Ostman et al.	29	629	4/12/77
ke	AD	4,548,451	Benarr et al.	339	17 M	4/27/84
ke	AE	3,842,189	Southgate	174	52	1/8/73
ke	AF	5,166,774	Banerji et al.	361	398	10/5/90
ke	AG	5,097,100	Jackson	174	94 R	1/25/91
ke	AH	5,071,359	Arnio et al.	439	91	4/27/90
ke	AI	2,869,040	Pifer	317	101	1/11/54
ke	AJ	5,109,596	Driller et al.	29	705	11/13/89
ke	AK	5,240,588	Uchida	205	125	8/27/92 -

FOREIGN PATENT DOCUMENTS

No.		Document No.	Date	Country	Class	Sub- Class	Trans- lation
ke	AL	WO 91/12706	8/22/91	WIPO			
	AM						
	AN						
	AO						
	AP						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	
	AS	
	AT	

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Examiner Initials	Document No.		Class	Sub- Class	Filing date if appropriate
le	3,662,454	Miller	29	470.1	3/18/70
le	4,707,657	Boegh-Petersen	324	158 F	1/12/85
le	5,525,545	Grube et al.	437	209	11/3/94
le	5,139,427	Boyd et al.	439	66	9/23/91
le	5,228,861	Grabbe	439	66	6/12/92
le	5,072,520	Nelson	29	852	10/23/90
le	5,237,743	Busacco et al.	29	885	6/19/92
le	5,245,751	Locke et al.	29	852	10/25/91
le	5,379,515	Kondo et al.	29	852	2/16/94
le	5,455,390	DiStefano et al.	174	262	2/1/94

No.							
	AL						
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	AN						
	AO						
	AP						

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Examiner Initials	Document No.		Class	Sub- Class	Filing date if appropriate
he	AA 5,414,298	Grube et al.	257	690	3/26/93
he	AB 5,442,282	Rostoker et al.	324	158.1	7/2/92
he	AC 5,495,667	Farnworth et al.	29	843	11/7/94
he	AD 5,189,507	Carlomagno et al.	257	777	6/7/91
he	AE 5,518,964	DiStefano et al.	437	209	7/7/94
he	AF 5,557,501	DiStefano et al.	361	704	11/18/94
he	AG 5,613,861	Smith et al.	439	81	6/7/95
he	AH 5,007,576	Congleton et al.	228	103	12/26/89
he	AI 5,045,410	Hiesbock et al.	428	644	7/3/89
he	AJ 5,047,711	Smith et al.	324	158	8/23/89
he	AK 5,059,143	Grabbe	439	886	9/8/88

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No.	Document No.	Date	Country	Class	Sub- Class	Trans- lation
he	AL 1003396	3/7/83	USSR			No
he	AM EP 0 708 338 A2	4/24/96	Europe			
he	AN 0 402 756 A2	12/19/90	Europe			
he	AO 0 593 966 A1	4/27/94	Europe			
he	AP 2 643 753	8/31/90	France			No

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

he	AR	Shih et al., "A Novel Elastomeric Connector for Packaging Interconnections, Testing and Burn-in Applications", IEEE Journal, May 21, 1995, pp. 126-133.
he	AS	Kong, et al., "Integrated electrostatically resonant scan tip for an atomic force microscope", J. Vac. Sci. Technol. B 11 (3), May/Jun 1993, pp. 634-641.
he	AT	"Compliant Lead Reform Tool and Process", IBM Technical Disclosure Bulletin, Vol. 31, No. 6, November 1988, pp. 160-162

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Examiner Initials		Document No.		Class	Sub-Class	Filing date if appropriate
<i>ve</i>	AA	5,066,907	Tarzwell et al.	324	158	2/6/90
<i>ve</i>	AB	5,095,187	Gliga	219	68	12/20/89
<i>ve</i>	AC	5,123,850	Elder et al.	439	67	6/7/91
<i>ve</i>	AD	5,136,367	Chiu	357	74	8/31/90
<i>ve</i>	AE	4,918,032	Jain et al.	437	228	7/8/88
<i>ve</i>	AF	4,998,885	Beaman	439	66	10/27/89
<i>ve</i>	AG	4,705,205	Allen et al.	228	180	5/14/84
<i>ve</i>	AH	4,724,383	Hart	324	158 F	5/3/85
<i>ve</i>	AI	4,732,313	Kobayashi et al.	228	179	7/26/85
<i>ve</i>	AJ	4,751,199	Phy	437	209	1/21/87
<i>ve</i>	AK	4,757,256	Whann et al.	324	158 P	5/1/87

FOREIGN PATENT DOCUMENTS

No.		Document No.	Date	Country	Class	Sub-Class	Translation
<i>ve</i>	AL	2 680 284	2/12/93	France			No
<i>ve</i>	AM	61287254	12/17/86	Japan (Abstract)			
<i>ve</i>	AN	61244057	10/30/86	Japan (Abstract)			
<i>ve</i>	AO	WO 96/02959	2/1/96	WIPO			
<i>ve</i>	AP	1 026 876	3/27/58	Germany			No

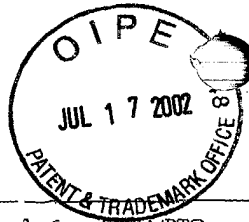
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

<i>ve</i>	AR	U. Renz, "Multipoint Test Probe for Printed Cards", IBM Technical Disclosure Bulletin, Vol. 17, No. 2, July 1974, pp. 2 pgs. total.
<i>ve</i>	AS	"Chip Column Package Structure", IBM Technical Disclosure Bulletin, Vol. 40, No. 08, August 1997, pp. 117-118.
<i>ve</i>	AT	Alan D. Knight, "MCM-TO-PRINTED WIRING BOARD (SECOND LEVEL) CONNECTION TECHNOLOGY OPTIONS", pp. 487-523.

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Modified Form PTO/SB/08A

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				<i>Complete If Known</i>	
				Application Number	09/295,269
				Filing Date	4/20/1999
				First Named Inventor	Khandros
				Group Art Unit	2841
				Examiner Name	K. Cuneo
Sheet	1	of	1	Attorney Docket No.	P2D7D1-US

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	U.S. Patent Number	Document Kind Code ²	Name of Patentee or Applicant	Publication Date	Relevant Portions

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Office ³	Document Number ⁴	Kind Code ⁵	Name of Patentee or Applicant	Publication Date	Relevant Portions

OTHER PRIOR ART - NONPATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
	A	WEAST, Handbook Of Chemistry and Physics (1975-1976), pp. D-171 to D-172, (CRC Press, Cleveland, Ohio)	

Examiner Signature:		Date Considered	9/8/02
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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.